



Dual N-Channel 100V (D-S) MOSFET

● **Features**

- $R_{DS(ON)} < 80m\Omega @ V_{GS} = 10V$
- $R_{DS(ON)} < 98m\Omega @ V_{GS} = 4.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

● **APPLICATIONS**

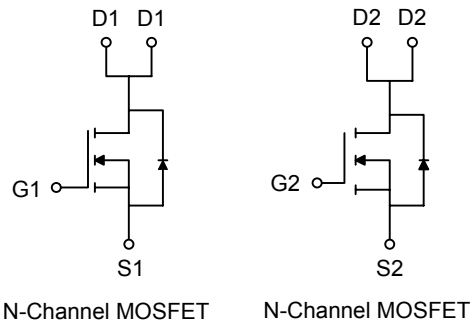
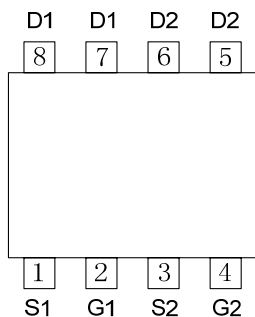
- Power Management in Note book
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC
- LCD Display inverter

● **GENERAL DESCRIPTION**

The FS4980 is the Dual N-Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching , and low in-line power loss are needed in a very small outline surface mount package.

● **Pin Configuration**

SOP8 (TopView)



● **Absolute Maximum Ratings @ $T_A = 25^{\circ}C$ unless otherwise specified**

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DSS}	100	V
Gate-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current	I_D	4	A
Pulsed Drain Current	I_{DM}	16	A
Maximum Power Dissipation	P_D	$T_A = 25^{\circ}C$	2
		$T_A = 70^{\circ}C$	1.3
Operating Junction Temperature	T_J	-55 to 150	$^{\circ}C$
Thermal Resistance-Junction to Ambient	$R_{\theta JA}$	62.5	$^{\circ}C/W$



Notes:

a. mounted on a 1in2 FR-4 board with 2oz. Copper in a still air environment at 25°C, the current rating is based on the DC (<10s) test conditions, for each single die.

b. Pulse Test: Pulse Width < 300 μs, Duty Cycle < 2%.

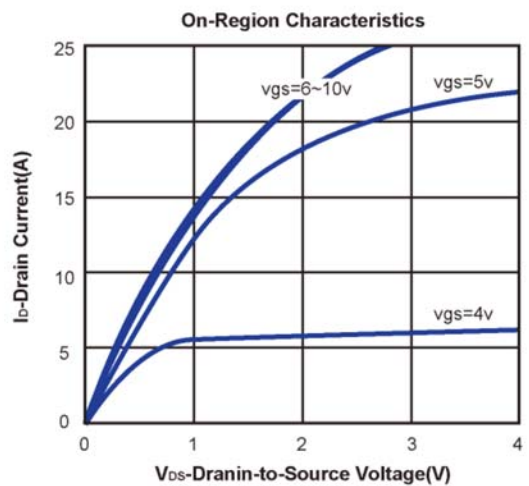
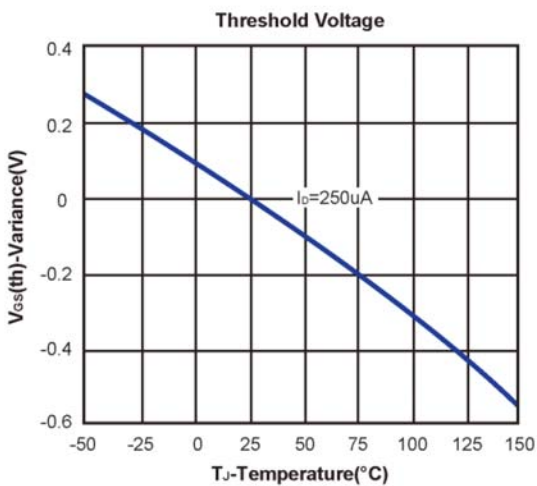
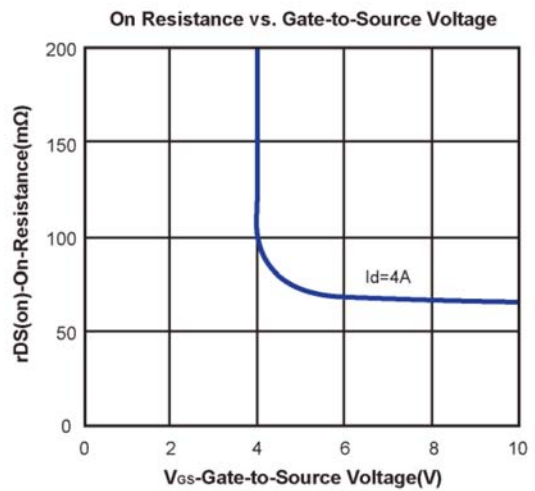
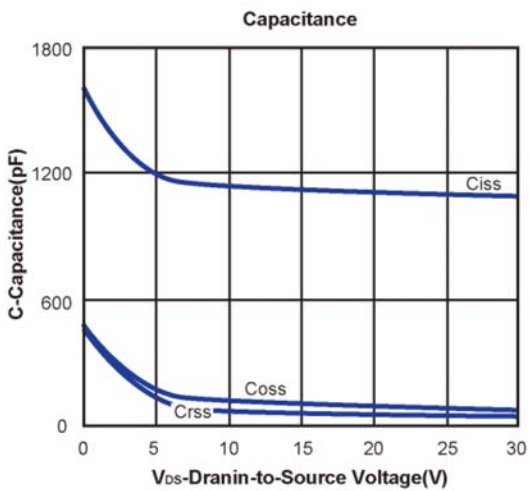
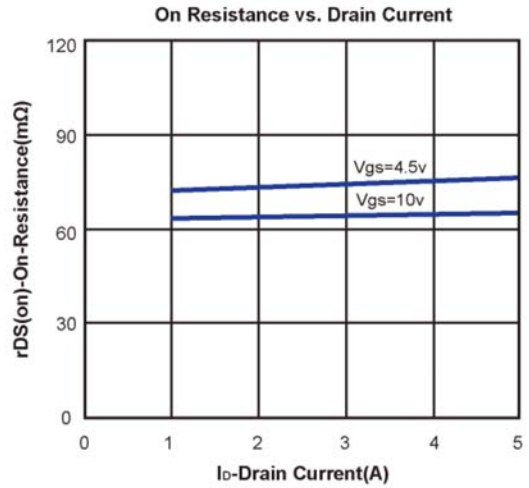
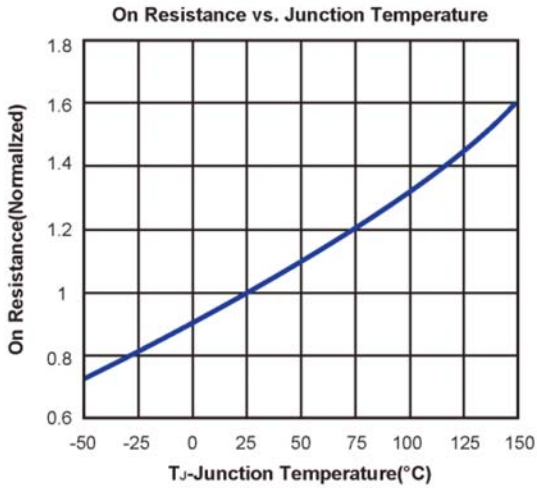
● **Electrical Characteristics @ T_A = 25°C unless otherwise specified**

Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0, I _D =250μA	100			V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1		2.5	V
I _{GSS}	Gate Body Leakage	V _{DS} =0V, V _{GS} =± 20V			±100	nA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =80V, V _{GS} =0V			1	μA
R _{DS(ON)}	Drain-Source On-Resistance(1)	V _{GS} =10V, I _D = 4A		65	80	mΩ
		V _{GS} =4.5V, I _D = 3.2A		75	98	
G _{FS}	Forward Transconductance	V _{DS} =10V, I _D =6.0A	7	13		S
V _{SD}	Diode Forward Voltage	I _S =12A, V _{GS} =0V			1.3	V
DYNAMIC						
Q _g	Total Gate Charge	V _{DS} =80V, V _{GS} =5V, I _D =4A		17.5		nC
Q _{gs}	Gate-Source Charge			10		
Q _{gd}	Gate-Drain Charge			5.5		
t _{d(on)}	Turn-On Time	V _{DD} =50V, R _L =12.5Ω, I _D =4A, V _{GEN} =5V, R _G =4.7Ω		27.5		nS
t _r	Turn-On Rise Time			90		
t _{d(off)}	Turn-Off Delay Time			35		
t _f	Turn-On Fall Time			11		
C _{iss}	Input capacitance	V _{DS} =10V, V _{GS} =0V, f=1.0MHz		1100		pF
C _{oss}	Output Capacitance			72		
C _{rss}	Reverse Transfer Capacitance			45		

Notes: (1) Pulse test; pulse width ≅ 300us, duty cycle ≅ 2%

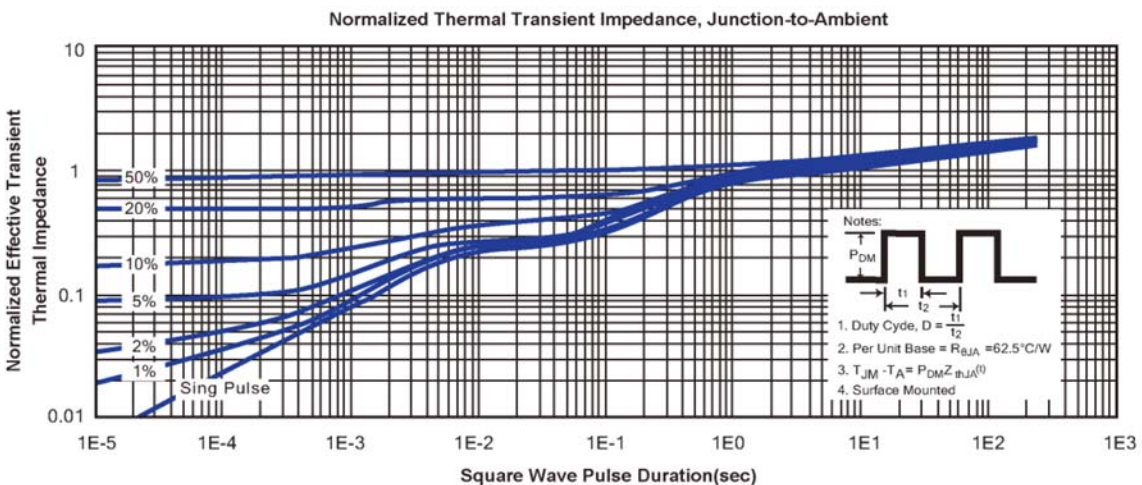
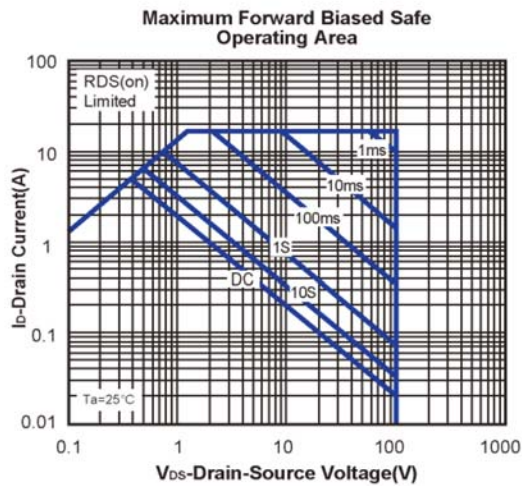
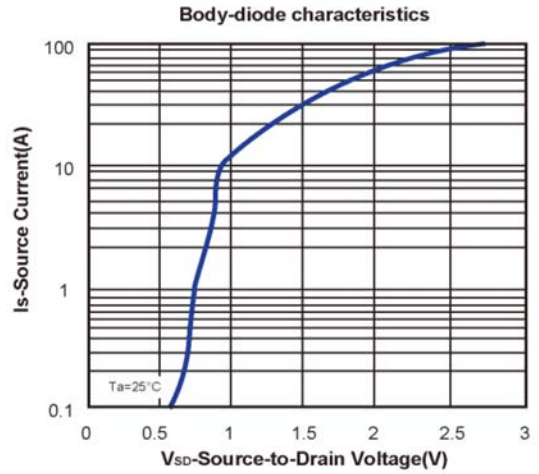
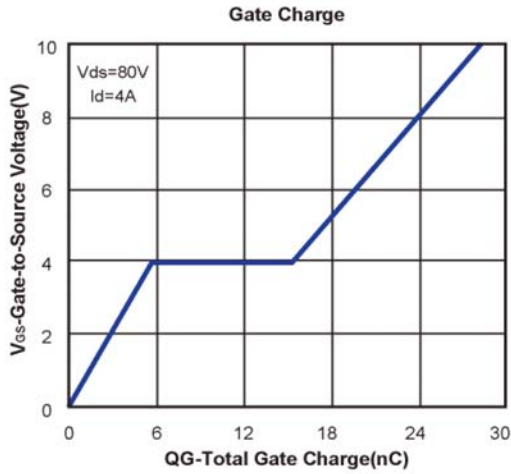


● Typical Performance Characteristics



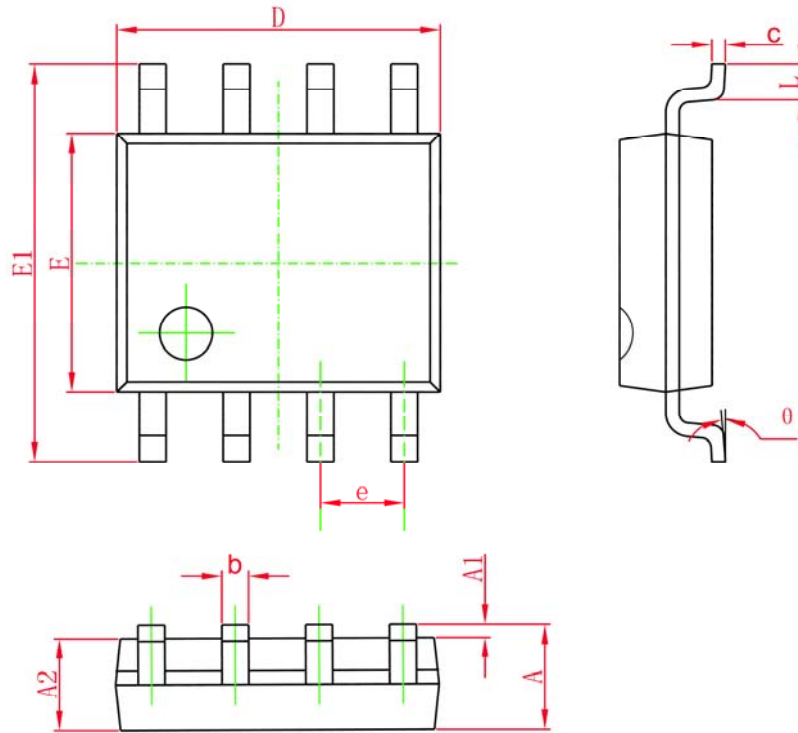


● Typical Performance Characteristics





● Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°